

Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/693,159	COBB ET AL.	
				Examiner	Art Unit	
				Devin Hanan	3745	

ORIGINAL				CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
415	119	415	206								
INTERNATIONAL CLASSIFICATION				417	312	423.1					
F	0	1	D	25/4							
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<i>Devin Hanan 11/17/05</i> Devin Hanan 11/17/205 (Assistant Examiner) (Date)				<i>Edward K. Look 11/25/05</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				Total Claims Allowed: 21			
<i>K. Cooper 11-30-05</i> (Legal Instruments Examiner) (Date)								O.G. Print Claim(s)	O.G. Print Fig.	1	2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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